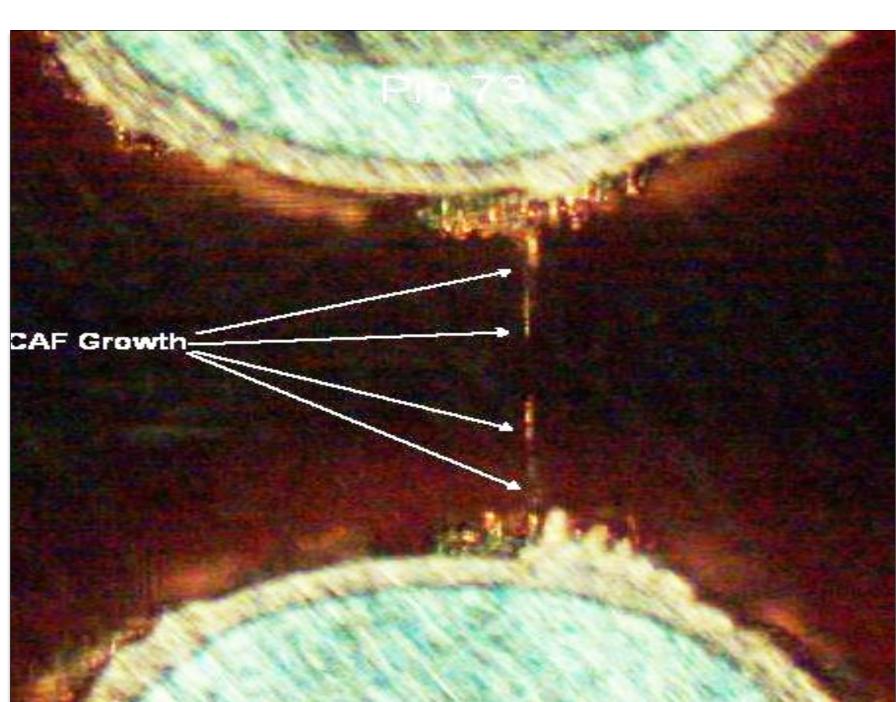
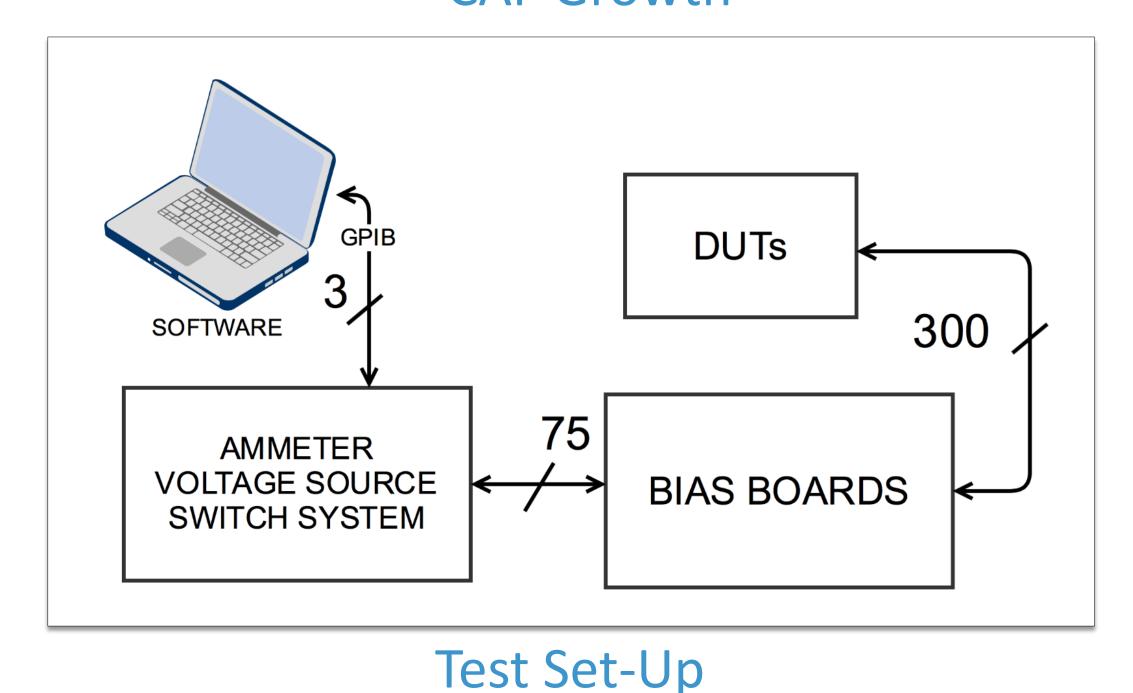
# Intel CAF Tester Development

## Background

- Intel aims to keep platforms for seven years or more, so they need to understand how small changes affect the lifetime of a product.
- A conductive anodic filament (CAF) is a conductive copper filament that forms in the dielectric material between two adjacent conductors in a printed circuit board (PCB).
- Need accelerated test environment, which includes high temperature, humidity, and voltage to model CAF failures over long periods of time.
- New PCB designs require tighter spacing between traces and vias, which increases the likelihood of CAF failures.
- Testing requires many devices as manufacturing and material variations will occur.



**CAF Growth** 



# Project Description

Intel would like to upgrade their current CAF testing system's hardware and software. The software needs to be upgraded to the MATLAB platform, and the hardware needs to be redesigned to ease test set up time.

# Project Impact

<u>Overview</u>	Before	After
Number of laptops required	3	1
Test setup time	8 hrs	1 hr
Required wire connections	600	75
Post test data processing	40 hrs	0 hrs
Software Features		
Pause test	no	yes
Show failure at a glance	no	yes
Data collection rate adjustment	no	yes
Data accessibility	Once	Λ ων
	Every	Any- time
	24 hrs	time
Continue from previous test	no	yes

Comparison Between Set-Ups

## Deliverables

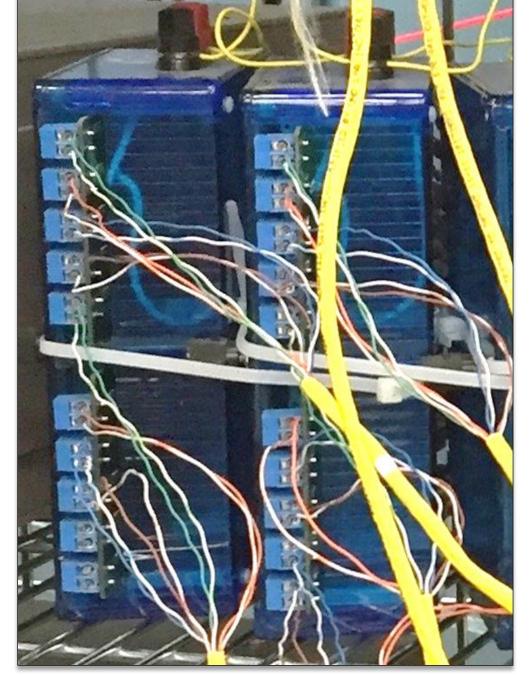
#### Software:

- Upgrade software from Visual Basic 6.0 to MATLAB 2015a
- Implement new features

#### Hardware:

- Redesign "bias" boxes
- Simplify test and decrease set-up time

## Results





#### **Previous CAF Set-up**

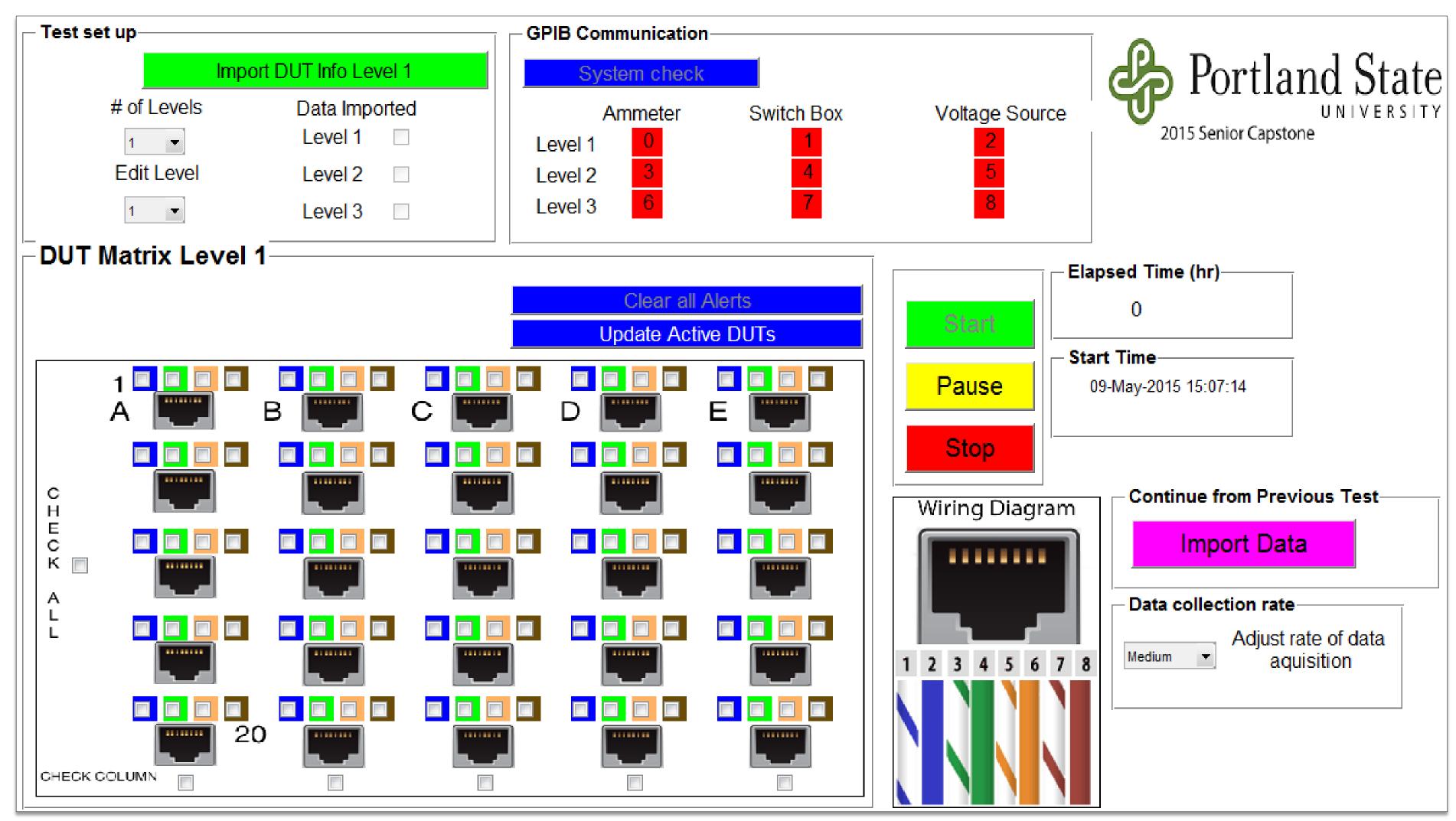
- Looked like a rats nest
- Time consuming setup (8+ hrs)
- Required 600 screw terminal connections

#### **New CAF Set-up**

- Easier wiring scheme reduces set up time by 90%.
- Compact design new CAF setup requires only 75 Ethernet connections for one test

Previous CAF Set-Up

New CAF Set-Up



### Upgraded MATLAB GUI

- GUI is user friendly, intuitive, and easy to maintain
- GUI is designed to match the physical interface of the new test setup
- Software compiles and handles millions of data points over thousands of hours
- Previous software only output time, current, and resistance. All other columns of data had to be manually populated, which required 40 hours of processing



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